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# NATIONAL STANDARD OF THE

# PEOPLE'S REPUBLIC OF CHINA

# GB 6624-1986

## Standard method for measuring the surface quality of polished silicon wafers by visual examination

硅抛光片表面质量目测检验方法

**(English Translation)**

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Document data

1 Document data

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Sector: National standard (Mandatory).

Status: obsolete, replaced by GB/T 6624-1995.



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